Electronic Supplementary Materials 1: Thin-film equations

Because we used a perpendicular initial angle of incidence in our colour measurements, only the formulae for the p-component of polarization are presented. Following Jellison (1993), we treated each interface as a matrix of the form

$$I_j = \begin{bmatrix} 1 & r_j \\ r_j & 1 \end{bmatrix}$$
[1]

where $r_j = (\tilde{n}_j \cos \phi_{j-1} - \tilde{n}_{j-1} \cos \phi_j) / (\tilde{n}_j \cos \phi_{j-1} + \tilde{n}_{j-1} \cos \phi_j).$

 \tilde{n}_j and \tilde{n}_{j-1} are the complex refractive indices (($\tilde{n} = n-ki$), where n= real refractive index and k = extinction coefficient) of the layer under consideration and the layer above it, respectively. ϕ_j and ϕ_{j-1} are the complex angles of incidence, calculated using Snell's law: $\tilde{n}_0 \sin \phi_0 = \tilde{n}_j \sin \phi_j$.

The transfer matrix incorporated the thickness of the jth layer:

$$L_{j} = \begin{bmatrix} \exp(ib_{j}) & 0\\ 0 & \exp(-ib_{j}) \end{bmatrix}$$
[2]

 $b_i = (2\pi d_i \tilde{n}_i \cos \phi_i)/\lambda$, where d_i is the thickness of the layer, and λ is the wavelength of light.

The total scattering matrix is then given by

$$S = \left(\prod_{j=1}^{N} I_j L_j\right) I_{N+1}, \qquad [3]$$

where *N* is the layer number. [4] The amplitude reflectivity (*r*) is $r = S_{21} / S_{11}$.

The final reflectance (*R*) is calculated as $R = rr^*$. [5]

Electronic Supplementary Materials 2: Example of nanostructural measurements

Transmission electron micrograph of an iridescent feather barbule illustrating measured nanostructural variables. C = Cortex, M = Melanin granules.



Electronic Supplementary Materials 3: Examples of the microanatomy of feather barbules of the species used in this study. All images are transmission electron micrographs, and scale bars in each case are 500 nm.





Red-winged blackbird

















